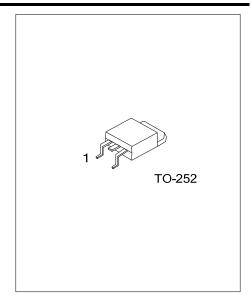
2NM65-FD **Power MOSFET** 

# 2A, 650V N-CHANNEL SUPER-JUNCTION MOSFET

#### DESCRIPTION

The UTC 2NM65-FD is a Super Junction MOSFET Structure. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance.

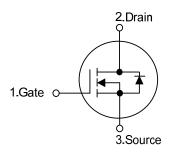
The UTC 2NM65-FD is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.



#### **FEATURES**

- \*  $R_{DS(ON)}$  < 2.6  $\Omega$  @  $V_{GS}$  = 10V,  $I_{D}$  =1.0A
- \* Fast switching capability
- \* Avalanche energy specified
- \* Improved dv/dt capability, high ruggedness

#### **SYMBOL**



#### **ORDERING INFORMATION**

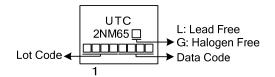
Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
2NM65L-TN3-R	2NM65G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



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#### **MARKING**





2NM65-FD **Power MOSFET** 

## ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{DSS}$	650	V
Gate-Source Voltage		$V_{GSS}$	±30	V
Drain Current	Continuous	$I_{D}$	2	Α
	Pulsed (Note 2)	$I_{DM}$	6	Α
Avalanche Energy	Single Pulsed (Note 3)	E <sub>AS</sub>	72	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	8	V/ns
Power Dissipation		$P_{D}$	44	W
Junction Temperature		$T_J$	+150	°C
Storage Temperature		$T_{STG}$	-55 ~ <b>+</b> 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=144mH,  $I_{AS}$ =1.0A,  $V_{DD}$ =50V,  $R_{G}$ =25  $\Omega$ , Starting  $T_{J}$  = 25°C
- 4.  $I_{SD} \le 2.0A$ , di/dt $\le 200A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25$ °C

#### **THERMAL DATA**

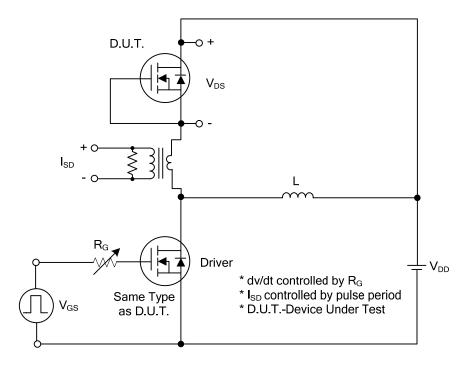
PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	100	°C/W	
Junction to Case	$\theta_{ m JC}$	2.8	°C/W	

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> =25°C, unless otherwise specified)

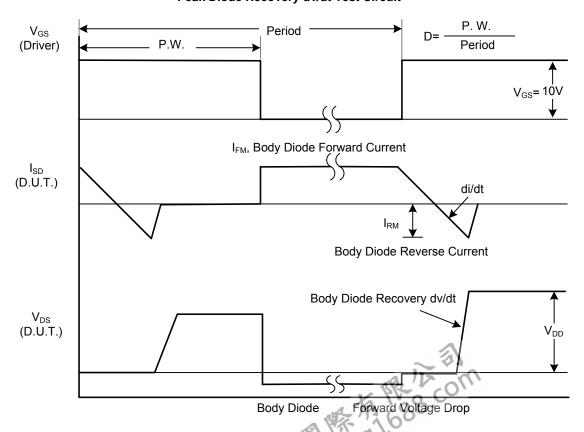
<u> </u>				<b></b>	<b>.</b>	<del></del>		
PARAMETER		SYMBOL	SYMBOL TEST CONDITIONS		TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650			V	
Drain-Source Leakage Current		$I_{DSS}$	$V_{DS} = 650V, V_{GS} = 0V$			10	μΑ	
Cata Cauraa Laakaga Current	Forward I <sub>G</sub>		$V_{GS} = 30V, V_{DS} = 0V$			100	nA	
Gate-Source Leakage Current		$I_{GSS}$	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA	
ON CHARACTERISTICS					-			
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V	
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	$V_{GS} = 10V, I_D = 1.0A$			2.6	Ω	
DYNAMIC CHARACTERISTICS								
Input Capacitance	put Capacitance				150		pF	
Output Capacitance	Output Capacitance		$V_{GS}$ =0V, $V_{DS}$ =25V, f =1MHz		140		pF	
Reverse Transfer Capacitance					12		pF	
<b>SWITCHING CHARACTERISTIC</b>	S							
Turn-On Delay Time (Note 1)	Turn-On Delay Time (Note 1)				1		ns	
Turn-On Rise Time		t <sub>D (ON)</sub> t <sub>R</sub>	$V_{DD}$ =300V, $V_{GS}$ =10V, $I_{D}$ =2.0A,		9		ns	
Turn-Off Delay Time		$t_{D(OFF)}$	R <sub>G</sub> =25Ω (Note 1, 2)		18		ns	
Turn-Off Fall Time		$t_{F}$			22		ns	
DRAIN-SOURCE DIODE CHARA	CTERISTICS	6						
Continuous Drain-Source Current		Is				2.0	Α	
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				6.0	Α	
Drain-Source Diode Forward Voltage (Note 1)		$V_{SD}$	I <sub>S</sub> =2.0A, V <sub>GS</sub> =0V			1.4	٧	
Rody Diode Payerse Pacovery Time (Note 1)		+	I <sub>S</sub> =2.0A, V <sub>GS</sub> =0V		110		nS	
Body Diode Reverse Recovery Ch	narge	Qrr	dl/dt=100A/µs		0.4		μC	
Notes: 1. Pulse Test: Pulse width	≤ 300µs, Dut	y cycle≤2%.	1/8 (20.					
<ol><li>Essentially independent</li></ol>	of operating	temperature.	A 1997-1700					
		A	(NO)					
		4 303	FIVIT					
Body Diode Reverse Recovery Charge Q <sub>rr</sub> dl/dt=100A/μs 0.4 μC  Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle≤2%.  2. Essentially independent of operating temperature.  3 of 6								
CINN								
UNISONIC TECHNOLOGIES CO., LTD					3 of 6			



#### ■ TEST CIRCUITS AND WAVEFORMS

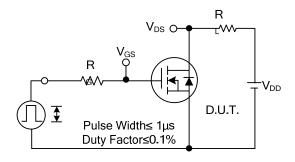


### Peak Diode Recovery dv/dt Test Circuit

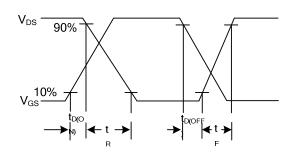


Peak Diode Recovery dv/dt Waveforms

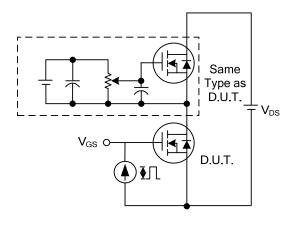
#### **TEST CIRCUITS AND WAVEFORMS**



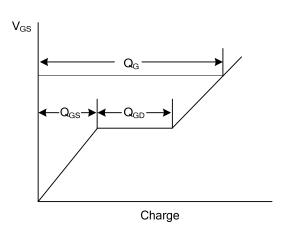
**Switching Test Circuit** 



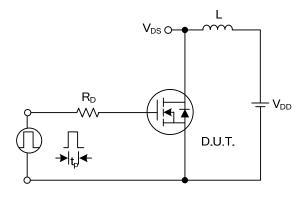
Switching Waveforms



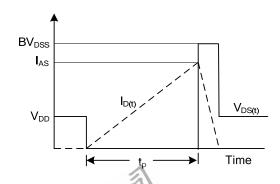
Gate Charge Test Circuit



Gate Charge Waveform

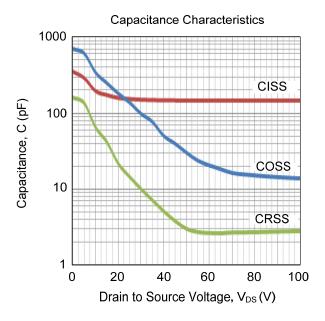


**Unclamped Inductive Switching Test Circuit** 



Unclamped Inductive Switching Waveforms

#### ■ TYPICAL CHARACTERISTICS



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